

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Deok-Yong KIM et al.

Serial No.: 10/749,670

Examiner: Rosario, Dennis

Filed: December 30, 2003

Art Unit: 2624

Confirmation No.: 9761

For: METHOD AND APPARATUS FOR DETECTING DEFECTS ON A  
WAFER

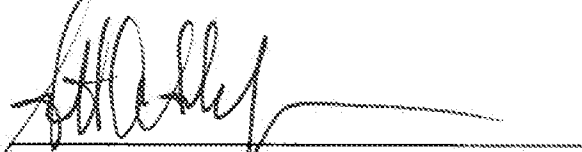
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**APPLICANT'S COMMENTS ON EXAMINER'S  
STATEMENT OF REASONS FOR ALLOWANCE**

In the Examiner's Statement of Reasons for Allowance, the Examiner recited portions of the allowed independent claims and stated that the prior art, either singularly or in combination, fails to teach or suggest the recited portions. The applications note that it is a well-known tenet of patent law that each allowed patent claim stands alone. Further, although the Examiner has indicated some reason for allowance, there can be other reasons that claims are allowable.

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Respectfully submitted,  
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